

TRANSISTOR MOS-FET DIODE

SEMICONDUCTOR TEST SYSTEM

半導体テストシステム

CAT1050M

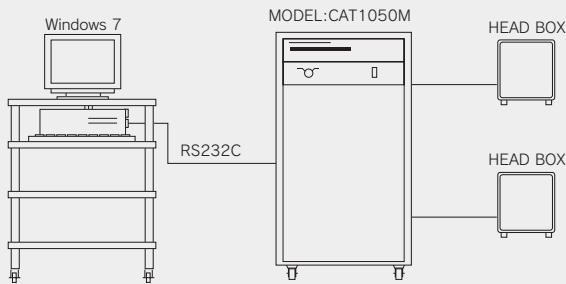
1000V
50A

2-MULTIPLEXER



System Configuration

※The combination with 8 PIN scanner is shown on this picture.※写真は8ピンスキャナーとの組み合わせです。



TRANSISTOR MOS-FET IGBT THYRISTOR DIODE

SEMICONDUCTOR TEST SYSTEM

半導体テストシステム

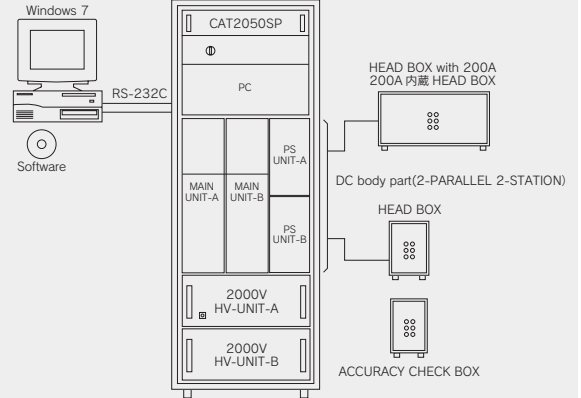
CAT2050SP

2000V
200A

2-PARALLEL



System Configuration



- The series of CAT testers have been designed to measure DC characteristics and have all types of Voltage : 500V-1500V, Current : 10A-50A. And models which more than 1500V and 50A are acceptable by option.
- Measurement station has 3 channels (at the maximum), and by setting in scanner makes it acceptable to multiple-pin devices.
- CATシリーズはDC特性をテストする測定器で、電圧500V～1500V、電流10A～50Aまでの各種タイプを用意。また、1500V、50A以上のモデルはオプションにて対応可能です。
- 測定ステーションは最大3チャンネルまで、スキャナを組み込むことにより多ピンデバイスの測定にも対応します。

MODEL	CAT1050M	CAT2050SP
SOFTWARE		
TEST PROGRAM	TBS(TEST-BY-SORT)	Test symbol names can be changed/Host CPU interfaceable by RS-232C
TEST PLAN/SORT PLAN	100/100	200/200
BIN OUT		24
DC UNIT		
TEST DEVICES	Transistor, MOS-FET, Diode	Transistor, MOS-FET, IGBT, Thyristor, Diode
VOLTAGE/CURRENT	999V/50A	2000V/200A
TEST ITEMS		
TRANSISTOR	ICE, ICB, IEB, ILCE, ILCB, ILEB, BVCE, BVCB, BVEB, IB, HFE, VCESAT, VBESAT, VFBC, VFBE, VFEC, BTON	
FET	IDS, IDG, ICEX(IE), IGX, IGSS, BVDS, BVDG, BVSG, BVGSS, VFGD, VFGS, VFSDS, VP, VTH, VDSON, RdsON, IDON, DHIDSS, GMP, GMV, GMI	IDS, IDG, IGX, IGSS, ISGS, BVDS, BVDG, BVSG, VFGD, VFGS, VFSDS, VP, VTH, VDSON, RdsON, IDON, DHIDSS, GMP, GMV, GMI
IGBT	—	ICE, IGES, BVCE, BVCG, BVEG, VFECs, VTH, VGE(th), VCEON, GMP
DIODE		IR, VR, VF
THYRISTOR	—	IDRM, IS, VRGM, VGK, VTM, VGT, IGT, IH, VDRM
DIMENSIONS & WEIGHT		
MAIN UNIT	360(W)×800(D)×700(H)…110kg	550(W)×860(D)×1700(H)…306kg
SCANNER	220(W)×475(D)×240(H)…20kg(1set)	—
HEAD BOX(CAT2050S)	—	220(W)×465(D)×240(H)…11kg
HEAD BOX(CAT2020ZS)	—	430(W)×700(D)×245(H)…26kg